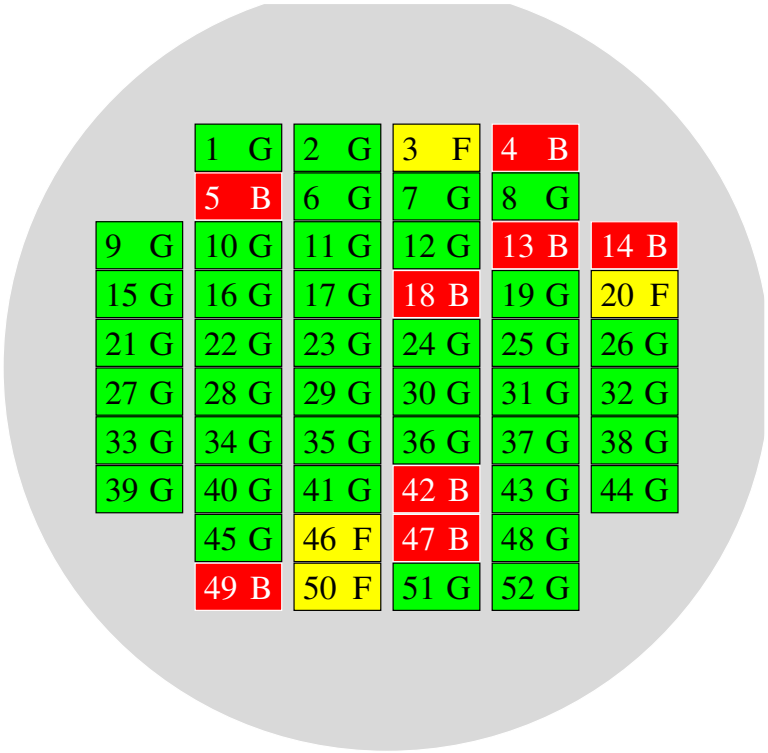
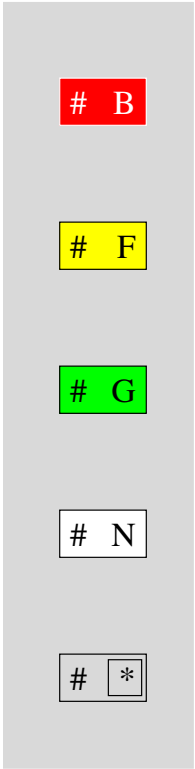
Die quality map for wafer 27 s/n: 21316-03-21 (not backplated)

Date: 11/01/98